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TMUX1219 ZHCSJR5-MAY 2019

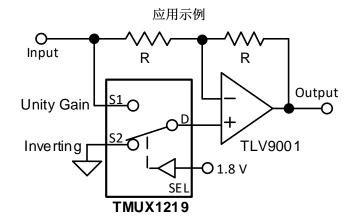
TMUX1219 5V 双向、2:1 通用开关

1 特性

- 轨至轨运行
- 双向信号路径
- 1.8V 逻辑兼容
- 失效防护逻辑
- 低导通电阻: 3Ω
- 宽电源电压范围: 1.08V 至 5.5V
- -40°C 至 +125°C 的工作温度
- 低电源电流: 4nA
- 转换时间: 14ns
- 先断后合开关
- ESD 保护 HBM: 2000V

2 应用

- 模拟和数字开关
- I2C 和 SPI 总线多路复用
- 远程无线电单元
- 条形码扫描仪
- 电机驱动器
- 楼宇自动化
- 模拟输入模块
- 电力输送
- 视频监控
- 电子销售终端
- 电器
- 消费类音频



3 说明

TMUX1219 是一款通用互补金属氧化物半导体 (CMOS) 单极双投 (SPDT) 开关。TMUX1219 可根据 SEL 引脚的状态在两个输入电源之间切换。1.08V 至 5.5V 的宽电源电压工作范围 可支持 从个人电子设备到 楼宇自动化的各种应用。该器件可在源极 (Sx) 和漏极 (D) 引脚上支持从 GND 到 V_{DD} 范围的双向模拟和数字 信号。4nA 的低电源电流可用于便携式 应用。

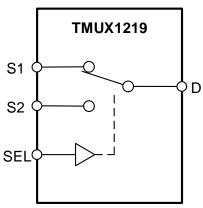
所有逻辑输入均具有兼容 1.8V 逻辑的阈值,当器件在 有效电源电压范围内运行时,这些阈值可确保 TTL 和 CMOS 逻辑兼容性。失效防护逻辑 电路允许在电源引 脚之前的控制引脚上施加电压,从而保护器件免受潜在 的损害。

器件信息(1)

器件型号	封装	封装尺寸(标称值)
TMUX1010	SC70 (6)	2.00mm × 1.25mm
TMUX1219	SOT-23 (6) ⁽²⁾	2.90mm x 1.60mm

(1) 如需了解所有可用封装,请参阅数据表末尾的封装选项附录。(2) 产品预览





Texas Instruments

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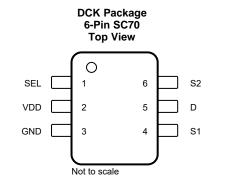
4 修订历史记录

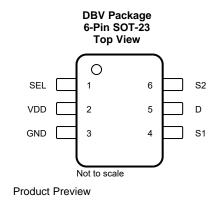
注: 之前版本的页码可能与当前版本有所不同。

日期	修订版本	说明
2019 年 5 月	*	初始发行版。



5 Pin Configuration and Functions





Pin Functions

Р	IN		DESCRIPTION
NAME	NO.	ITPE''	DESCRIPTION
SEL	1	Ι	Select pin: controls state of the switch according to $\frac{1}{5}$ 1. (Logic Low = S1 to D, Logic High = S2 to D)
VDD	2	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{DD} and GND.
GND	3	Р	Ground (0 V) reference
S1	4	I/O	Source pin 1. Can be an input or output.
D	5	I/O	Drain pin. Can be an input or output.
S2	6	I/O	Source pin 2. Can be an input or output.

(1) I = input, O = output, I/O = input and output, P = power



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾⁽²⁾

		MIN	MAX	UNIT
V _{DD}	Supply voltage	-0.5	6	V
V _{SEL}	Logic control input pin voltage (SEL)	-0.5	6	V
I _{SEL}	Logic control input pin current (SEL)	-30	30	mA
$V_{S} \text{ or } V_{D}$	Source or drain voltage (Sx, D)	-0.5	V _{DD} +0.5	V
$I_S \text{ or } I_D (CONT)$	Source or drain continuous current (Sx, D)	-30	30	mA
T _{stg}	Storage temperature	-65	150	°C
TJ	Junction temperature		150	°C

(1) Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 or ANSI/ESDA/JEDEC JS-002, all pins ⁽²⁾	±750	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V _{DD}	Supply voltage	1.08	5.5	V
$\rm V_S$ or $\rm V_D$	Signal path input/output voltage (source or drain pin) (Sx, D)	0	V _{DD}	V
V _{SEL}	Logic control input pin voltage (SEL)	0	5.5	V
T _A	Ambient temperature	-40	125	°C

6.4 Thermal Information

		TMUX1219	
	THERMAL METRIC ⁽¹⁾	SC70 (DCK)	UNIT
		6 PINS	
$R_{ ext{ heta}JA}$	Junction-to-ambient thermal resistance	243.1	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	206.0	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	128.3	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	107.8	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	128.0	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



6.5 Electrical Characteristics ($V_{DD} = 5 \text{ V} \pm 10 \text{ \%}$)

at $T_A = 25^{\circ}C$, $V_{DD} = 5 V$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TA	MIN TYP	MAX	UNIT
ANALO	G SWITCH		- I			
		$V_{\rm S} = 0$ V to $V_{\rm DD}$	25°C	3		Ω
R _{ON}	On-resistance	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C		5	Ω
		Refer to On-Resistance	-40°C to +125°C		6	Ω
		$V_{\rm S} = 0$ V to $V_{\rm DD}$	25°C	0.15		Ω
ΔR_{ON}	On-resistance matching between channels	I _{SD} = 10 mA	-40°C to +85°C		0.4	Ω
		Refer to On-Resistance	-40°C to +125°C		5 5 6 0.4 1 3 2 2 40 5 25 40 5 0.87 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 80 50 50 80 50 50 80 50 50 50 80 50 50 80 50 50 80 50 80 50 50 80 50 50 50 80 50 50 50 50 50 50 50 50 50 5	Ω
		$V_{\rm S} = 0 \text{ V to } V_{\rm DD}$	25°C	1.5		Ω
R _{ON}	On-resistance flatness	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C	2		Ω
FLAT		Refer to On-Resistance	-40°C to +125°C	3		Ω
		$V_{DD} = 5 V$	25°C	±5		nA
	Course off looks as surrout (1)	Switch Off	-40°C to +85°C	-25	25	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	$V_D = 4.5 V / 1.5 V$ $V_S = 1.5 V / 4.5 V$ Refer to Off-Leakage Current	-40°C to +125°C	-40	40	nA
		V _{DD} = 5 V	25°C	±15		nA
D(ON)	Channel on leakage current	Switch On	-40°C to +85°C	-50	50	nA
I _{S(ON)}		$V_D = V_S = 4.5 V / 1.5 V$ Refer to On-Leakage Current	-40°C to +125°C	-80	80	nA
LOGIC	INPUTS (SEL)			I		
VIH	Input logic high		-40°C to +125°C	1.49	5.5	V
V _{IL}	Input logic low		-40°C to +125°C	0	0.87	V
l _{IH} I _{IL}	Input leakage current		25°C	±0.005		μA
I _{IH} I _{IL}	Input leakage current		-40°C to +125°C		±0.05	μA
C _{IN}	Logic input capacitance		25°C	1		pF
C _{IN}	Logic input capacitance		-40°C to +125°C		2	pF
POWER	SUPPLY					
I		Logic inputs $= 0.1/$ or $5.5.1/$	25°C	0.003		μA
IDD	V _{DD} supply current	Logic inputs = 0 V or 5.5 V	-40°C to +125°C		1.5	μA

(1) When V_S is 4.5 V, V_D is 1.5 V or when V_S is 1.5 V, V_D is 4.5 V.

Electrical Characteristics (V_{DD} = 5 V ±10 %) (continued)

at $T_A = 25^{\circ}C$, $V_{DD} = 5 V$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT
DYNAN	IC CHARACTERISTICS						
		$V_{\rm S} = 3 V$	25°C		12		ns
t _{TRAN}	Switching time between channels	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C			18	ns
		Refer to Transition Time	-40°C to +125°C			19	ns
		$V_{\rm S} = 3 V$	25°C		8		ns
t _{OPEN}	Break before make time	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C	1			ns
(BBM)		Refer to Break-Before-Make	-40°C to +125°C	1			ns
Q _C	Charge Injection	$V_D = 1 V$ $R_S = 0 \Omega$, $C_L = 1 nF$ Refer to Charge Injection	25°C		-10		рС
0	Off Instation		25°C		-65		dB
O _{ISO}	Off Isolation	$ \begin{array}{l} R_{L} = 50 \ \Omega, \ C_{L} = 5 \ pF \\ f = 10 \ MHz \\ Refer to \ Off \ Isolation \end{array} $	25°C		-45		dB
×	Crosstalk	$ \begin{array}{l} R_{L} = 50 \ \Omega, \ C_{L} = 5 \ pF \\ f = 1 \ MHz \\ Refer to \ Crosstalk \end{array} $	25°C		-65		dB
X _{TALK}	Crosstalk	$ \begin{array}{l} R_{L} = 50 \ \Omega, \ C_{L} = 5 \ pF \\ f = 10 \ MHz \\ Refer to \ Crosstalk \end{array} $	25°C		-45		dB
BW	Bandwidth	$R_L = 50 \Omega, C_L = 5 pF$ Refer to Bandwidth	25°C		250		MHz
C_{SOFF}	Source off capacitance	f = 1 MHz	25°C		7		pF
C _{SON} C _{DON}	On capacitance	f = 1 MHz	25°C		23		pF



6.6 Electrical Characteristics ($V_{DD} = 3.3 \text{ V} \pm 10 \text{ \%}$)

at $T_A = 25^{\circ}C$, $V_{DD} = 3.3 \text{ V}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TA	MIN TYP	MAX	UNIT
ANALO	OG SWITCH	<u>.</u>		1		
		$V_{\rm S} = 0$ V to $V_{\rm DD}$	25°C	5		Ω
R _{ON}	On-resistance	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C		10	Ω
		Refer to On-Resistance	-40°C to +125°C		12	Ω
		$V_{S} = 0 V \text{ to } V_{DD}$	25°C	0.15		Ω
ΔR_{ON}	On-resistance matching between channels	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C		1	Ω
		Refer to On-Resistance	-40°C to +125°C		10 12 1 1 1 1 25 40 25 40 50 80 50 80 50 80 50 80 50 80 50 80 2 5.5 0.8	Ω
		$V_{\rm S} = 0$ V to $V_{\rm DD}$	25°C	3.5		Ω
R _{ON}	On-resistance flatness	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C	4		Ω
FLAT		Refer to On-Resistance	-40°C to +125°C	5		Ω
		V _{DD} = 3.3 V	25°C	±5		nA
		Switch Off	-40°C to +85°C	-25	25	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	$V_D = 3 V / 1 V$ $V_S = 1 V / 3 V$ Refer to Off-Leakage Current	-40°C to +125°C	-40	40	nA
		V _{DD} = 3.3 V	25°C	±15		nA
I _{D(ON)}	Channel on leakage current	Switch On	-40°C to +85°C	-50	50	nA
I _{S(ON)}		$V_D = V_S = 3 V / 1 V$ Refer to On-Leakage Current	-40°C to +125°C	-80	80	nA
LOGIC	INPUTS (SEL)			1		
VIH	Input logic high		-40°C to +125°C	1.35	5.5	V
V _{IL}	Input logic low		-40°C to +125°C	0	0.8	V
I _{IH} I _{IL}	Input leakage current		25°C	±0.005		μA
I _{IH} I _{IL}	Input leakage current		-40°C to 125°C		±0.05	μA
C _{IN}	Logic input capacitance		25°C	1		pF
C _{IN}	Logic input capacitance		-40°C to +125°C		2	pF
	SUPPLY					
		Logic inputs $-0.1/$ or $5.5.1/$	25°C	0.003		μA
I _{DD}	V _{DD} supply current	Logic inputs = 0 V or 5.5 V	-40°C to +125°C		0.8	μA

(1) When V_S is 3 V, V_D is 1 V or when V_S is 1 V, V_D is 3 V.

Electrical Characteristics (V_{DD} = 3.3 V ±10 %) (continued)

at $T_A = 25^{\circ}C$, $V_{DD} = 3.3$	V (unless otherwise	noted)

	PARAMETER	TA	MIN	TYP	MAX	UNIT	
DYNA	IC CHARACTERISTICS		i.				
		V _S = 2 V	25°C		14		ns
t _{TRAN}	Switching time between channels	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C			20	ns
		Refer to Transition Time	-40°C to +125°C			21	ns
		$V_{\rm S} = 2 V$	25°C		9		ns
t _{OPEN}	Break before make time	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C	1			ns
(BBM)		Refer to Break-Before-Make	-40°C to +125°C	1			ns
Q _C	Charge Injection						
	$R_L = 50 \Omega$, $C_L = 5 pF$ f = 1 MHz Refer to Off Isolation	25°C		-65		dB	
O _{ISO}	Off Isolation	$R_L = 50 \Omega, C_L = 5 pF$ f = 10 MHz Refer to Off Isolation	25°C		-45		dB
v	Createlly	$ \begin{array}{l} R_L = 50 \; \Omega, C_L = 5 \; pF \\ f = 1 \; MHz \\ Refer to Crosstalk \end{array} $	25°C		-65		dB
X _{TALK} Crosstalk	f = 10		25°C		-45		dB
BW	Bandwidth	$R_L = 50 \Omega, C_L = 5 pF$ Refer to Bandwidth	25°C		250		MHz
C_{SOFF}	Source off capacitance	f = 1 MHz	25°C		7		pF
C _{SON} C _{DON}	On capacitance	f = 1 MHz	25°C		23		pF



6.7 Electrical Characteristics ($V_{DD} = 1.8 \text{ V} \pm 10 \text{ \%}$)

at $T_A = 25^{\circ}C$, $V_{DD} = 1.8$ V (unless otherwise noted)

	PARAMETER	PARAMETER TEST CONDITIONS TA					UNIT	
ANALO	OG SWITCH	-						
		$V_{\rm S} = 0$ V to $V_{\rm DD}$	25°C		40		Ω	
R _{ON}	On-resistance	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C			80	Ω	
		Refer to On-Resistance	-40°C to +125°C			80	Ω	
		$V_{S} = 0 V \text{ to } V_{DD}$	25°C		0.4		Ω	
ΔR_{ON}	On-resistance matching between channels	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C			1.5	Ω	
		Refer to On-Resistance	-40°C to +125°C			1.5	Ω	
		V _{DD} = 1.98 V	25°C		±5		nA	
	0	Switch Off	-40°C to +85°C	-25		25	nA	
I _{S(OFF)}	S(OFF) Source on leakage current /	V _S	$V_D = 1.62 \text{ V} / 1 \text{ V}$ $V_S = 1 \text{ V} / 1.62 \text{ V}$ Refer to Off-Leakage Current	-40°C to +125°C	-40		40	nA
		V _{DD} = 1.98 V	25°C		±15		nA	
I _{D(ON)}	Channel on leakage current	Switch On	-40°C to +85°C	-50		50	nA	
I _{S(ON)}		$V_D = V_S = 1.62 \text{ V} / 1 \text{ V}$ Refer to On-Leakage Current	-40°C to +125°C	-80		80	nA	
LOGIC	INPUTS (SEL)							
V _{IH}	Input logic high		-40°C to +125°C	1.07		5.5	V	
V _{IL}	Input logic low		-40°C to +125°C	0		0.68	V	
I _{IH} I _{IL}	Input leakage current		25°C		±0.005		μA	
I _{IH} I _{IL}	Input leakage current		-40°C to +125°C			±0.05	μA	
CIN	Logic input capacitance		25°C		1		pF	
C _{IN}	Logic input capacitance		-40°C to +125°C			2	pF	
POWER	R SUPPLY	·						
	M suggiture suggest		25°C		0.001		μA	
IDD	V _{DD} supply current	Logic inputs = 0 V or 5.5 V	-40°C to +125°C			0.6	μA	

(1) When V_S is 1.62 V, V_D is 1 V or when V_S is 1 V, V_D is 1.62 V.

Electrical Characteristics (V_{DD} = 1.8 V ±10 %) (continued)

at $T_A = 25^{\circ}$ C, $V_{DD} = 1.8$ V (unless otherwise noted)

PARAMETER		TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT
DYNA	IC CHARACTERISTICS	1					
		25°C		28		ns	
t _{TRAN}	Transition time between channels	$V_{S} = 1 V$ R _L = 200 Ω, C _L = 15 pF	-40°C to +85°C			44	ns
		Refer to Transition Time	-40°C to +125°C			44	ns
		$V_{\rm S} = 1 V$	25°C		16		ns
	Break before make time	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C	1			ns
(BBM)		Refer to Break-Before-Make	–40°C to +125°C	1			ns
Q _C	Charge Injection						рС
		$R_L = 50 \Omega$, $C_L = 5 pF$ f = 1 MHz Refer to Off Isolation	25°C		-65		dB
O _{ISO}	Off Isolation	$R_L = 50 \Omega, C_L = 5 pF$ f = 10 MHz Refer to Off Isolation	25°C		-45		dB
v	Crosstalk	$ \begin{array}{l} R_{L} = 50 \; \Omega, C_{L} = 5 \; pF \\ f = 1 \; MHz \\ Refer to \ Crosstalk \end{array} $	25°C		-65		dB
X _{talk}	Crosstaik		25°C		-45		dB
BW	Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		250		MHz
C _{SOFF}	Source off capacitance	f = 1 MHz	25°C		7		pF
C _{SON} C _{DON}	On capacitance	f = 1 MHz	25°C		23		pF



6.8 Electrical Characteristics ($V_{DD} = 1.2 \text{ V} \pm 10 \text{ \%}$)

at $T_A = 25^{\circ}C$, $V_{DD} = 1.2$ V (unless otherwise noted)

	PARAMETER	PARAMETER TEST CONDITIONS TA					UNIT
ANALO	OG SWITCH	-		I.			
	$V_{\rm S} = 0$ V to $V_{\rm DD}$		25°C		70		Ω
R _{ON}	On-resistance	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C			105	Ω
		Refer to On-Resistance	-40°C to +125°C			105	Ω
		$V_{S} = 0 V \text{ to } V_{DD}$	25°C		0.4		Ω
ΔR_{ON}	On-resistance matching between channels	$I_{SD} = 10 \text{ mA}$	-40°C to +85°C			1.5	Ω
		Refer to On-Resistance	-40°C to +125°C			1.5	Ω
		V _{DD} = 1.32 V	25°C		±5		nA
		Switch Off	-40°C to +85°C	-25		25	nA
I _{S(OFF)}	S(OFF) Source off leakage current ⁽¹⁾	$V_D = 1 V / 0.8 V$ $V_S = 0.8 V / 1 V$ Refer to Off-Leakage Current	-40°C to +125°C	-40		40	nA
		V _{DD} = 1.32 V	25°C		±15		nA
I _{D(ON)}	Channel on leakage current	Switch On	-40°C to +85°C	-50		50	nA
I _{S(ON)}		$V_D = V_S = 1 V / 0.8 V$ Refer to On-Leakage Current	-40°C to +125°C	-80		80	nA
LOGIC	INPUTS (SEL)						
V _{IH}	Input logic high		-40°C to +125°C	0.96		5.5	V
V _{IL}	Input logic low		-40°C to +125°C	0		0.36	V
I _{IH} I _{IL}	Input leakage current		25°C		±0.005		μA
I _{IH} I _{IL}	Input leakage current		-40°C to +125°C			±0.05	μA
CIN	Logic input capacitance		25°C		1		pF
C _{IN}	Logic input capacitance		-40°C to +125°C			2	pF
POWER	RSUPPLY		- ·				
	N		25°C		0.003		μA
I _{DD}	V _{DD} supply current	Logic inputs = 0 V or 5.5 V	-40°C to +125°C			0.5	μA

(1) When V_S is 1 V, V_D is 0.8 V or when V_S is 0.8 V, V_D is 1 V.

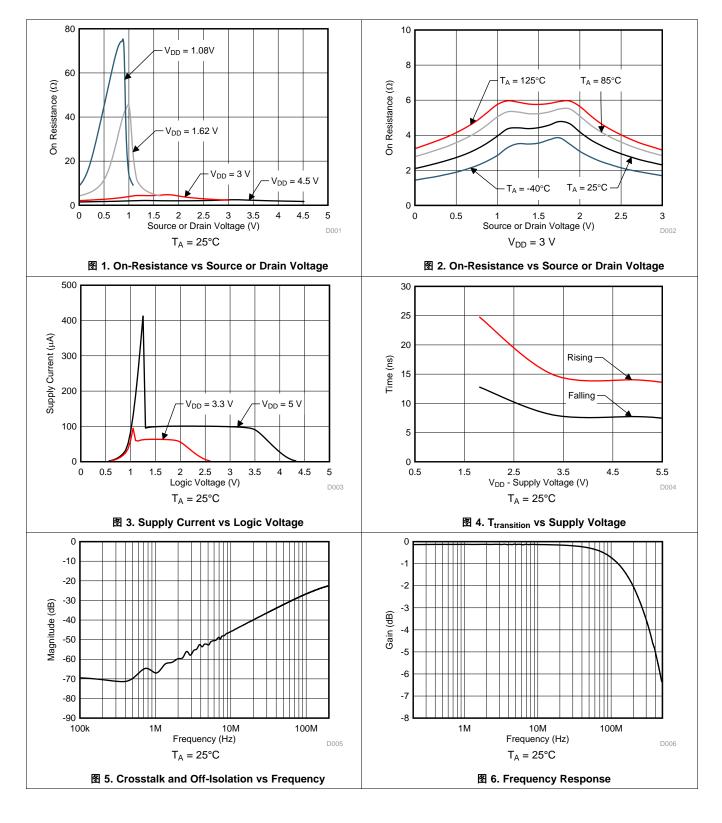
Electrical Characteristics (V_{DD} = 1.2 V ±10 %) (continued)

at $T_A = 25^{\circ}$ C, $V_{DD} = 1.2$ V (unless otherwise noted)

PARAMETER		METER TEST CONDITIONS TA					UNIT
DYNAN	IC CHARACTERISTICS		i.				
		V _S = 1 V	25°C		55		ns
t _{TRAN}	Transition time between channels	$R_{L} = 200 \Omega, C_{L} = 15 pF$	-40°C to +85°C			190	ns
		Refer to Transition Time	-40°C to +125°C			190	ns
		$V_{S} = 1 V$	25°C		28		ns
t _{OPEN} (BBM)	Break before make time	5		1			ns
(DDIVI)		Refer to Break-Before-Make	-40°C to +125°C	1			ns
Q _C	Charge Injection	$V_D = 1 V$ $R_S = 0 \Omega$, $C_L = 1 nF$ Refer to Charge Injection	25°C			рС	
0		$R_L = 50 \Omega$, $C_L = 5 pF$ f = 1 MHz Refer to Off Isolation	25°C		-65		dB
O _{ISO}	Off Isolation	$R_L = 50 \Omega, C_L = 5 pF$ f = 10 MHz Refer to Off Isolation	25°C		-45		dB
v	Crosstalk	$ \begin{array}{l} R_L = 50 \ \Omega, \ C_L = 5 \ pF \\ f = 1 \ MHz \\ Refer to \ Crosstalk \end{array} $	25°C		-65		dB
X _{talk}	Clossiaik		25°C		-45		dB
BW	Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		250		MHz
C _{SOFF}	Source off capacitance	f = 1 MHz	25°C		7		pF
C _{SON} C _{DON}	On capacitance	f = 1 MHz	25°C		23		pF



at $T_A = 25^{\circ}C$, $V_{DD} = 5 V$ (unless otherwise noted)



7 Parameter Measurement Information

7.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. The measurement setup used to measure R_{ON} is shown in \mathbb{Z} 7. Voltage (V) and current (I_{SD}) are measured using this setup, and R_{ON} is computed with $R_{ON} = V / I_{SD}$:

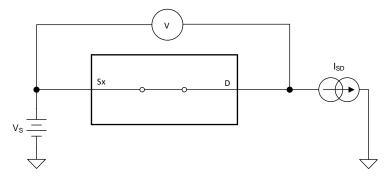


图 7. On-Resistance Measurement Setup

7.2 Off-Leakage Current

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

The setup used to measure off-leakage current is shown in **8** 8.

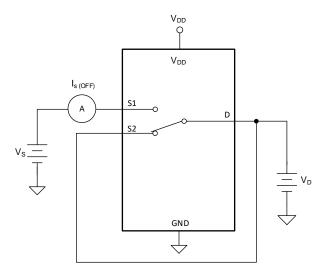


图 8. Off-Leakage Measurement Setup





7.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. \mathbb{B} 9 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

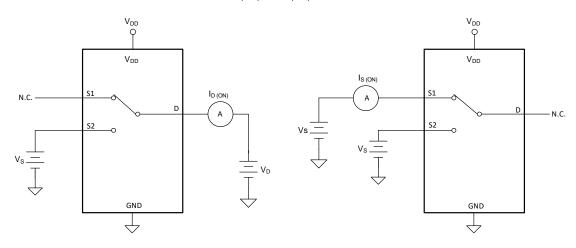


图 9. On-Leakage Measurement Setup

7.4 Transition Time

Transition time is defined as the time taken by the output of the device to rise or fall 10% after the logic control signal has risen or fallen past the logic threshold. The 10% transition measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. \mathbb{E} 10 shows the setup used to measure transition time, denoted by the symbol t_{TRANSITION}.

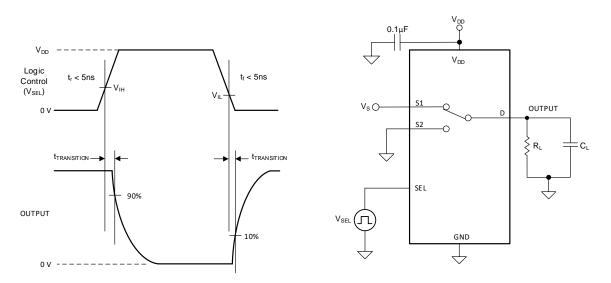


图 10. Transition-Time Measurement Setup

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7.5 Break-Before-Make

Break-before-make delay is a safety feature that prevents two inputs from connecting when the device is switching. The output first breaks from the on-state switch before making the connection with the next on-state switch. The time delay between the *break* and the *make* is known as break-before-make delay. 🛚 11 shows the setup used to measure break-before-make delay, denoted by the symbol t_{OPEN(BBM)}.

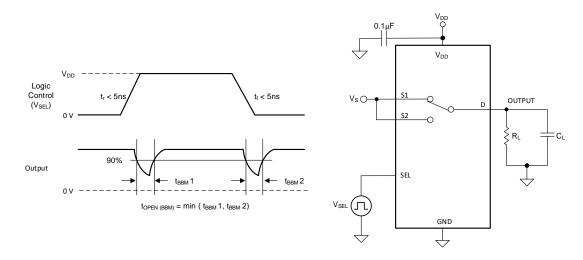


图 11. Break-Before-Make Delay Measurement Setup

7.6 Charge Injection

The TMUX1219 has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_c . If 12 shows the setup used to measure charge injection from Drain (D) to Source (Sx).

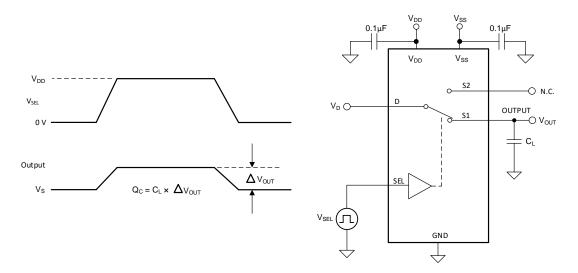


图 12. Charge-Injection Measurement Setup



7.7 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (Sx) of an off-channel. 🛽 13 shows the setup used to measure, and the equation used to calculate off isolation.

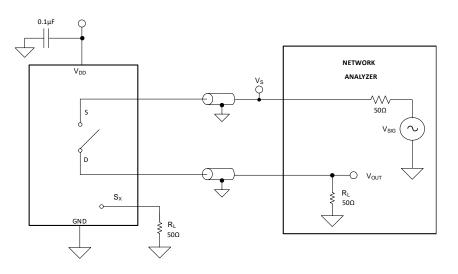


图 13. Off Isolation Measurement Setup

Off Isolation =
$$20 \cdot \text{Log}\left(\frac{V_{\text{OUT}}}{V_{\text{S}}}\right)$$
 (1)

7.8 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. B 14 shows the setup used to measure, and the equation used to calculate crosstalk.

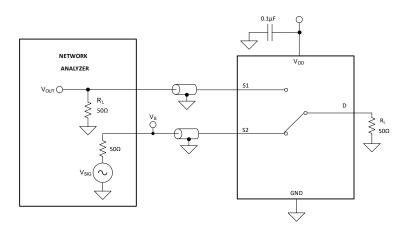


图 14. Crosstalk Measurement Setup

Channel-to-Channel Crosstalk =
$$20 \cdot Log\left(\frac{V_{OUT}}{V_S}\right)$$

(2)



7.9 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device. 15 shows the setup used to measure bandwidth.

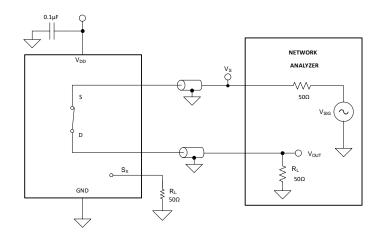


图 15. Bandwidth Measurement Setup



8 Detailed Description

8.1 Functional Block Diagram

The TMUX1219 is an 2:1 (SPDT), 1-channel switch where the input is controlled with a single select (SEL) control pin.

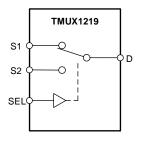


图 16. TMUX1219 Functional Block Diagram

8.2 Feature Description

8.2.1 Bidirectional Operation

The TMUX1219 conducts equally well from source (Sx) to drain (D) or from drain (D) to source (Sx). The device has very similar characteristics in both directions and supports both analog and digital signals.

8.2.2 Rail to Rail Operation

The valid signal path input/output voltage for TMUX1219 ranges from GND to V_{DD}.

8.2.3 1.8 V Logic Compatible Inputs

The TMUX1219 has 1.8-V logic compatible control for the logic control input (SEL). The logic input threshold scales with supply but still provides 1.8-V logic control when operating at 5.5 V supply voltage. 1.8-V logic level inputs allow the TMUX1219 to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and BOM cost. For more information on 1.8 V logic implementations refer to *Simplifying Design with 1.8 V logic Muxes and Switches*

8.2.4 Fail-Safe Logic

The TMUX1219 supports Fail-Safe Logic on the control input pin (SEL) allowing for operation up to 5.5 V, regardless of the state of the supply pin. This feature allows voltages on the control pin to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the select pin of the TMUX1219 to be ramped to 5.5 V while $V_{DD} = 0$ V. Additionally, the feature enables operation of the TMUX1219 with $V_{DD} = 1.2$ V while allowing the select pin to interface with a logic level of another device up to 5.5 V.

8.3 Device Functional Modes

The select (SEL) pin of the TMUX1219 controls which source channel is connected to the drain of the device. When a signal path is not selected, that source pin is in high impedance mode (HI-Z). The control pin can be as high as 5.5 V.

8.4 Truth Tables

CONTROL LOGIC (SEL)	Selected Source (Sx) Connected To Drain (D) Pin
0	S1
1	S2

表 1. TMUX1219 Truth Table

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9 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TMUX12xx family offers good system performance across a wide operating supply (1.08V to 5.5V). These devices include 1.8V logic compatible control input pins that enable operation in systems with 1.8V I/O rails. Additionally, the control input pin supports Fail-Safe Logic which allows for operation up to 5.5V, regardless of the state of the supply pin. This protection stops the logic pins from back-powering the supply rail. These features of the TMUX12xx, a family of general purpose multiplexers and switches, reduce system complexity, board size, and overall system cost.

9.2 Typical Application

9.2.1 Switchable Operational Amplifier Gain Setting

One example application of the TMUX1219 is to change an Op Amp from unity gain setting to an inverting amplifier configuration. Utilizing a switch allows a system to have a configurable gain and allows the same architecture to be utilized across the board for various inputs to the system. 图 17 shows the TMUX1219 configured for gain setting application.

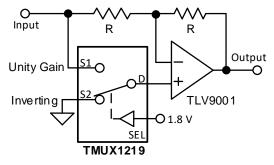


图 17. Switchable Op Amp Gain Setting

9.2.1.1 Design Requirements

This design example uses the parameters listed in $\frac{1}{5}$ 2.

表 2. Design Parameters

PARAMETERS	VALUES			
Input Signal	0 V to 2.75 V			
Mux Supply (V _{DD})	2.75 V			
Op Amp Supply (V ₊ / V ₋)	±2.75 V			
Mux I/O signal range	0 V to V _{DD} (Rail to Rail)			
Control logic thresholds	1.8 V compatible (up to 5.5V)			



9.2.1.2 Detailed Design Procedure

The application shown in 17 demonstrates how to use a single control input and toggle between gain settings of -1 and +1. If switching between inverting and unity gain is not required, the TMUX1219 can be utilized in the feedback path to select different feedback resistors and provide scalable gain settings for configurable signal conditioning.

The TMUX1219 can be operated without any external components except for the supply decoupling capacitors. The select pin is recommended to have a weak pull-down or pull-up resistor to ensure the input is in a known state. All inputs to the switch must fall within the recommend operating conditions of the TMUX1219 including signal range and continuous current. For this design with a supply of 2.75 V the signal range can be 0 V to 2.75 V and the max continuous current can be 30 mA.

9.2.1.3 Application Curve

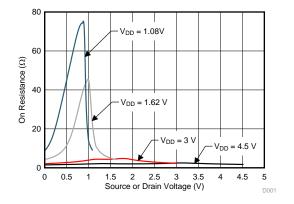




图 18. On-Resistance vs Source or Drain Voltage

9.2.2 Input Control for Power Amplifier

Another application of the TMUX1219 is for input control of a power amplifier. Utilizing a switch allows a system to control when the DAC is connected to the power amplifier, and can stop biasing the power amplifier by switching the gate to GND. 🛛 19 shows the TMUX1219 configured for control of the power amplifier.

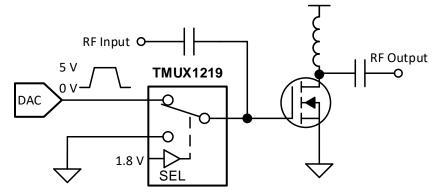


图 19. Input Control of Power Amplifier

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9.2.2.1 Design Requirements

This design example uses the parameters listed in 表 2.

PARAMETERS	VALUES			
Supply (V _{DD})	5 V			
Mux I/O signal range	0 V to V _{DD} (Rail to Rail)			
Control logic thresholds	1.8 V compatible (up to 5.5V)			

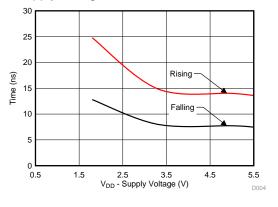
表 3. Design Parameters

9.2.2.2 Detailed Design Procedure

The application shown in 🕅 19 demonstrates how to toggle between the DAC output and GND for control of a power amplifier using a single control input. The DAC output is utilized to bias the gate of the power amplifier and can be disconnected from the circuit using the select pin of the switch. The TMUX1219 can support 1.8-V logic signals on the control input, allowing the device to interface with low logic controls of an FPGA or MCU. The TMUX1219 can be operated without any external components except for the supply decoupling capacitors. The select pin is recommended to have a weak pull-down or pull-up resistor to ensure the input is in a known state. All inputs to the switch must fall within the recommend operating conditions of the TMUX1219 including signal range and continuous current. For this design with a supply of 5 V the signal range can be 0 V to 5 V and the max continuous current can be 30 mA.

9.2.2.3 Application Curve

A key parameter for this application is the transition time of the device. Faster transition time allows the system to toggle between input sources at a faster rate and allows the output to settle to the final value. The TMUX1219 has a transition time that varies with supply voltage and is shown in 8 20



 $T_A = 25^{\circ}C$

图 20. T_{transition} vs Supply Voltage

10 Power Supply Recommendations

The TMUX1219 operates across a wide supply range of 1.08 V to 5.5 V. Do not exceed the absolute maximum ratings because stresses beyond the listed ratings can cause permanent damage to the devices.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the V_{DD} supply to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F from V_{DD} to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes.

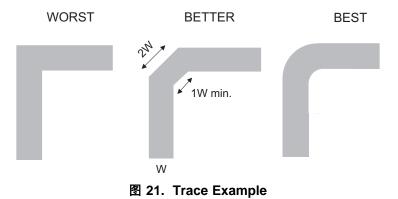


11 Layout

11.1 Layout Guidelines

11.1.1 Layout Information

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. 😰 21 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.



Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

图 22 illustrates an example of a PCB layout with the TMUX1219. Some key considerations are:

- Decouple the V_{DD} pin with a 0.1-µF capacitor, placed as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the V_{DD} supply.
- Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.

11.2 Layout Example

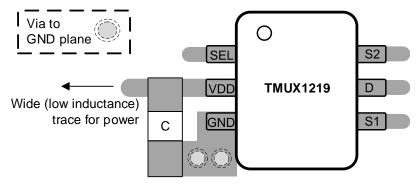


图 22. TMUX1219 Layout Example

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12 器件和文档支持

12.1 文档支持

12.1.1 相关文档

德州仪器 (TI),《使用低 CON 多路复用器改善稳定性问题》。

德州仪器 (TI),《使用 1.8V 逻辑多路复用器和开关简化设计》。

德州仪器 (TI), 《利用关断保护信号开关消除电源排序》。

德州仪器 (TI), 《高电压模拟多路复用器的系统级保护》。

12.2 接收文档更新通知

要接收文档更新通知,请导航至 TI.com.cn 上的器件产品文件夹。单击右上角的通知我进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

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Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 商标

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ESD的损坏小至导致微小的性能降级,大至整个器件故障。精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更, 恕不另行通知, 且 不会对此文档进行修订。如需获取此数据表的浏览器版本, 请查阅左侧的导航栏。

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10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TMUX1219DBVR	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	26IT	Samples
TMUX1219DCKR	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1F5	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGE MATERIALS INFORMATION

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Texas Instruments

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TMUX1219DBVR	SOT-23	DBV	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TMUX1219DCKR	SC70	DCK	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3

TEXAS INSTRUMENTS

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PACKAGE MATERIALS INFORMATION

5-Jun-2020



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TMUX1219DBVR	SOT-23	DBV	6	3000	180.0	180.0	18.0
TMUX1219DCKR	SC70	DCK	6	3000	180.0	180.0	18.0

DBV0006A



PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.2. This drawing is subject to change without notice.3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation. 5. Refernce JEDEC MO-178.



DBV0006A

EXAMPLE BOARD LAYOUT

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



DBV0006A

EXAMPLE STENCIL DESIGN

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



DCK (R-PDSO-G6)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
 - D. Falls within JEDEC MO-203 variation AB.



LAND PATTERN DATA



NOTES:

- A. All linear dimensions are in millimeters.B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



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